

## Electronic Supplementary Information (ESI)

# Impact of Band-gap Graded Structures Artificially Implemented in Mg-ZnO Epitaxial Films on Photoelectrochemical Properties

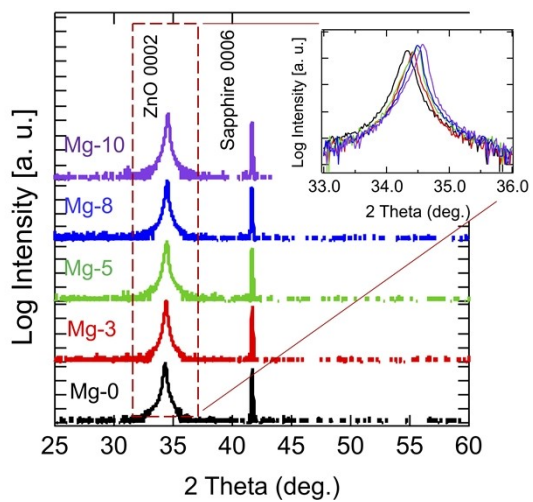
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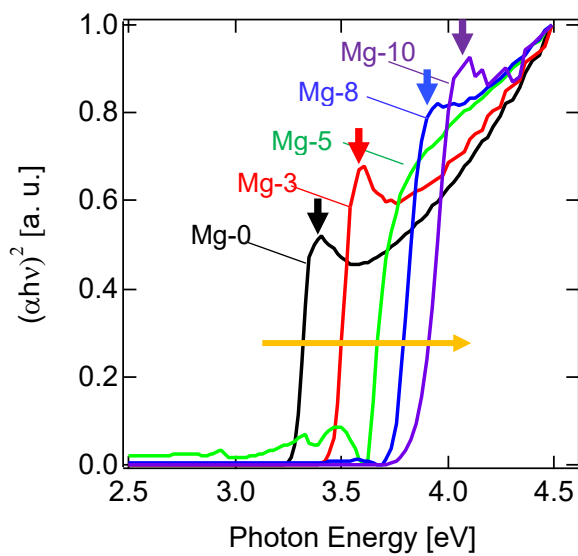
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	Sample Mg-0	Sample Mg-3	Sample Mg-5	Sample Mg-8	Sample Mg-10
Mg by WDS	0	–	10.5	15.3	18.0

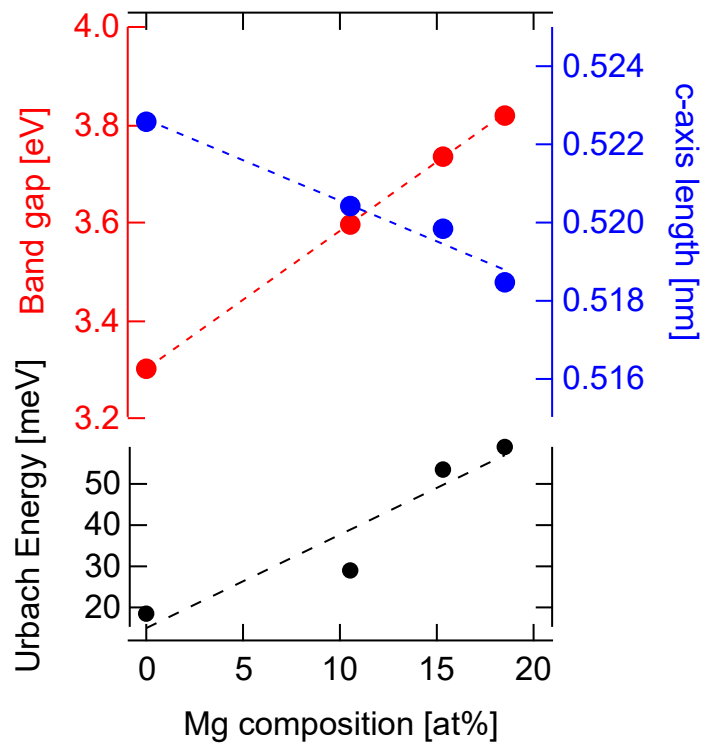
**Table S1 Mg composition estimated by WDS**



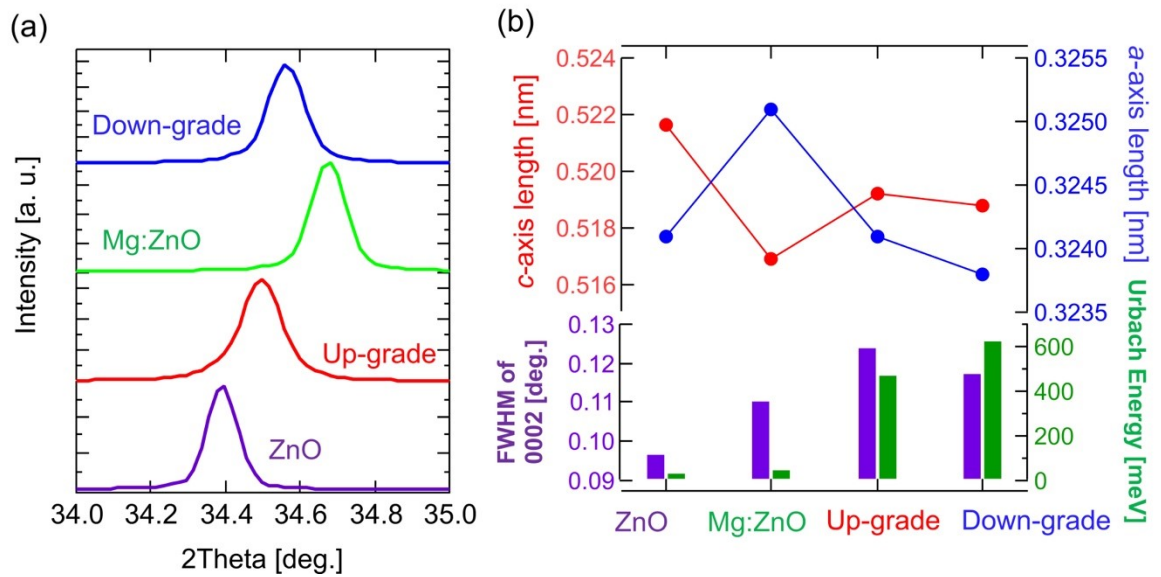
**Figure S1** XRD patterns of Mg-doped ZnO films with different nominal Mg compositions of 0 to 10 at%.



**Figure S2** Tauc plots from the optical absorption spectra of Mg-doped ZnO films with different nominal Mg compositions of 0 to 10 at%. The arrows indicate the peak positions assigned to an excitonic absorption.



**Figure S3** Linear relationships of the band gap, the *c*-axis length and the Urbach energy to the Mg composition. Here, it should be noted that the data points for Sample Mg-3 were missing in the plots due to no WDS data of its Mg composition as listed in Table S1.



**Figure S4** For ZnO, Mg:ZnO, up-grade and down-grade Mg-ZnO films, (a) XRD patterns in linear scale intensity, (b) Plots of the *a*- and *c*-axis parameters, the FWHM values of the 0002 peak in the  $\theta$ - $2\theta$  scan, and the Urbach energy values.